

IRFR4510PbF

HEXFET® Power MOSFET

IRFU4510PbF

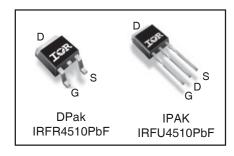


- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

V _{DSS}	100V
R _{DS(on)} typ.	11.1m Ω
max.	13.9m Ω
I _{D (Silicon Limited)}	63A
I _{D (Package Limited)}	56A

Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free



G	D	S
Gate	Drain	Source

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, VGS @ 10V (Silicon Limited)	63	
_D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	45	A
_D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	56	A
DM	Pulsed Drain Current ①	252	
P _D @T _C = 25°C	Maximum Power Dissipation	143	W
	Linear Derating Factor	0.95	W/°C
/ _{GS}	Gate-to-Source Voltage	± 20	V
Гл	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
_	Soldering Temperature, for 10 seconds	300	
	(1.6mm from case)		

Avalanche Characteristics

E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ©	127	mJ			
I _{AR}	Avalanche Current ①	See Fig. 14, 15, 22a, 22b	Α			
EAR	Repetitive Avalanche Energy ①		mJ			

Thermal Resistance

111011110111101111100						
Symbol	Parameter	Тур.	Max.	Units		
$R_{\theta JC}$	Junction-to-Case ®		1.05			
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ^⑦		50	°C/W		
$R_{\theta,JA}$	Junction-to-Ambient		110			

ORDERING INFORMATION:

See detailed ordering and shipping information on the last page of this data sheet.

Static @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.10		V/°C	Reference to 25°C, I _D = 5mA ^①
R _{DS(on)}	Static Drain-to-Source On-Resistance		11.1	13.9	mΩ	$V_{GS} = 10V, I_D = 38A \oplus$
$V_{GS(th)}$	Gate Threshold Voltage	2.0	3.0	4.0	V	$V_{DS} = V_{GS}, I_{D} = 100 \mu A$
I _{DSS}	Drain-to-Source Leakage Current			20	μA	$V_{DS} = 100V, V_{GS} = 0V$
				250	μA	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	n 1	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-100	nA	V _{GS} = -20V
R _{G(int)}	Internal Gate Resistance		0.61		Ω	

Dynamic @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	62			S	$V_{DS} = 25V, I_{D} = 38A$
Q_g	Total Gate Charge		54	81		$I_D = 38A$
Q_{gs}	Gate-to-Source Charge		14		nC	$V_{DS} = 50V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		15			V _{GS} = 10V ④
Q _{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})		39			$I_D = 38A, V_{DS} = 0V, V_{GS} = 10V$
t _{d(on)}	Turn-On Delay Time		18			$V_{DD} = 65V$
t _r	Rise Time		42]	$I_D = 38A$
t _{d(off)}	Turn-Off Delay Time		42		ns	$R_G = 7.5\Omega$
t _f	Fall Time		34			V _{GS} = 10V ④
C _{iss}	Input Capacitance		3031			$V_{GS} = 0V$
Coss	Output Capacitance		213			$V_{DS} = 50V$
C _{rss}	Reverse Transfer Capacitance		104		pF	f = 1.0MHz
Coss eff. (ER)	Effective Output Capacitance (Energy Related)		255			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 80V $ ©
C _{oss} eff. (TR)	Effective Output Capacitance (Time Related)		478			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 80V $

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			56		MOSFET symbol
	(Body Diode)			30	A	showing the
I _{SM}	Pulsed Source Current			252] ^	integral reverse
	(Body Diode) ①			232		p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 38A$, $V_{GS} = 0V$ ④
dv/dt	Peak Diode Recovery		7.0		V/ns	$T_J = 175$ °C, $I_S = 38A$, $V_{DS} = 100V$ ③
t _{rr}	Reverse Recovery Time		34		ns	$T_J = 25^{\circ}C$ $V_R = 86V$
			39		115	$T_J = 125^{\circ}C$ $I_F = 38A$
Q_{rr}	Reverse Recovery Charge		47		nC	$T_J = 25^{\circ}C$ di/dt = 100A/ μ s $\textcircled{9}$
			61		IIC	$T_J = 125$ °C
I _{RRM}	Reverse Recovery Current		2.4		Α	$T_J = 25^{\circ}C$
t _{on}	Forward Turn-On Time	Intrinsio	turn-on	time is r	negligibl	e (turn-on is dominated by LS+LD)

2 www.irf.com

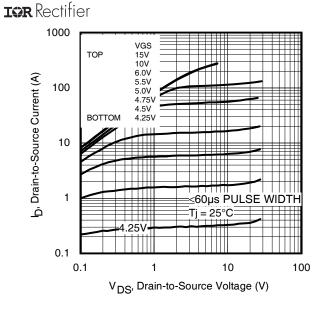


Fig 1. Typical Output Characteristics

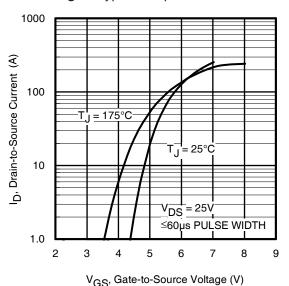


Fig 3. Typical Transfer Characteristics

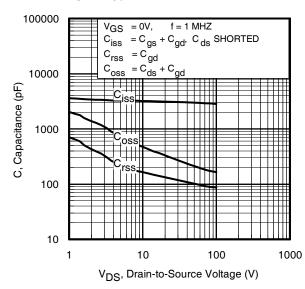


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage www.irf.com

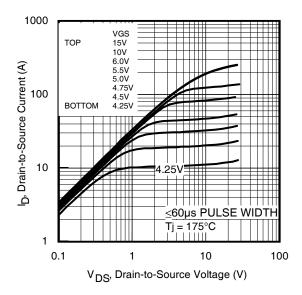


Fig 2. Typical Output Characteristics

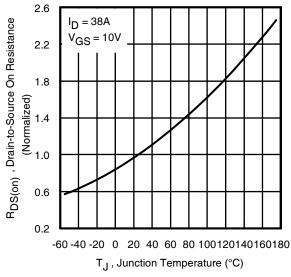


Fig 4. Normalized On-Resistance vs. Temperature

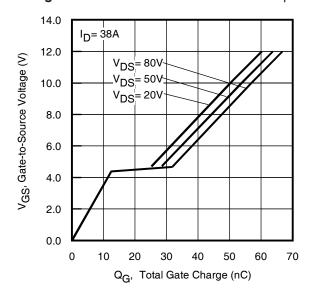


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

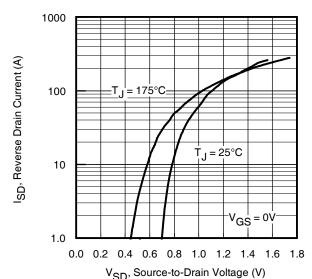
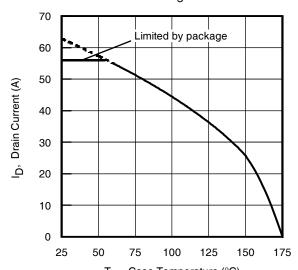
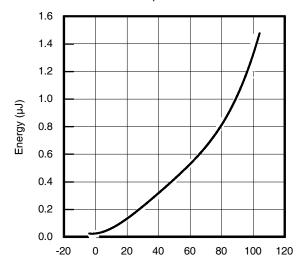


Fig 7. Typical Source-Drain Diode Forward Voltage



T_C, Case Temperature (°C) **Fig 9.** Maximum Drain Current vs.

Case Temperature



 $V_{DS,}$ Drain-to-Source Voltage (V) Fig 11. Typical C_{OSS} Stored Energy

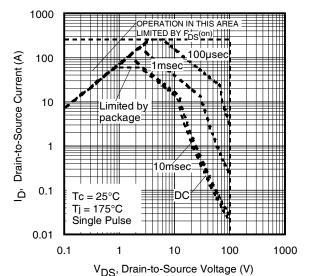


Fig 8. Maximum Safe Operating Area

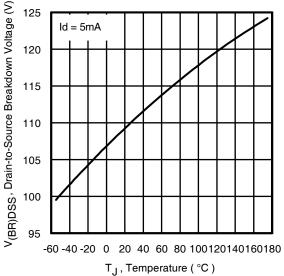


Fig 10. Drain-to-Source Breakdown Voltage

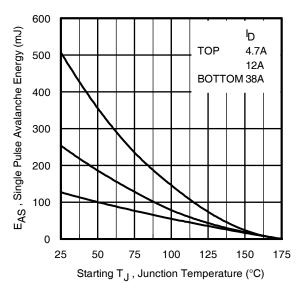


Fig 12. Maximum Avalanche Energy vs. DrainCurrent www.irf.com

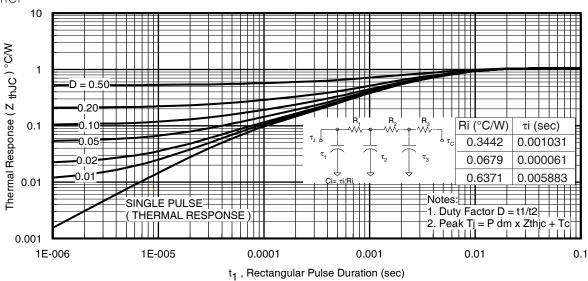


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

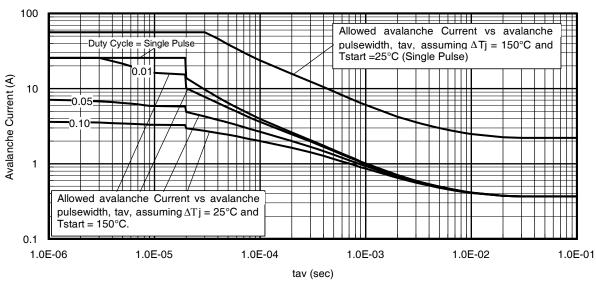


Fig 14. Typical Avalanche Current vs. Pulsewidth

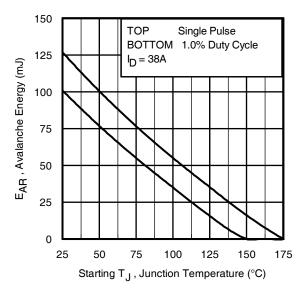


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
- Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{imax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
- 4. $P_{D (ave)}$ = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).

 t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \triangle T / \; Z_{thJC} \\ I_{av} &= 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

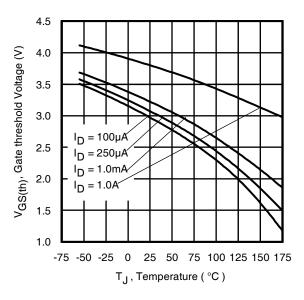


Fig 16. Threshold Voltage vs. Temperature

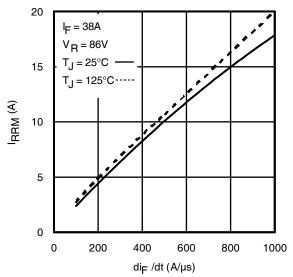


Fig. 18 - Typical Recovery Current vs. dif/dt

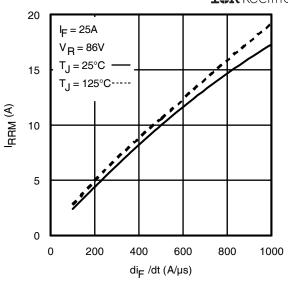


Fig. 17 - Typical Recovery Current vs. di_f/dt

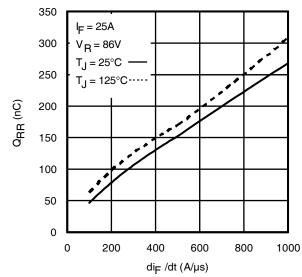


Fig. 19 - Typical Stored Charge vs. dif/dt

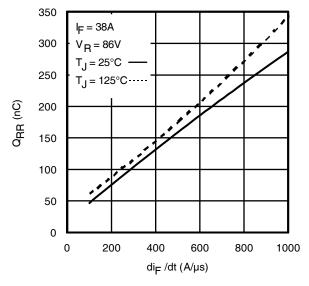


Fig. 20 - Typical Stored Charge vs. dif/dt

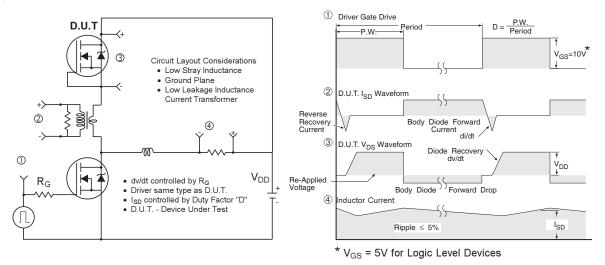


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

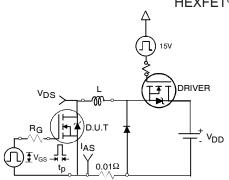


Fig 22a. Unclamped Inductive Test Circuit

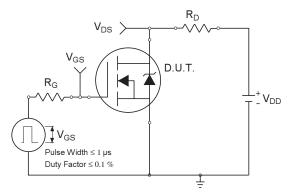


Fig 23a. Switching Time Test Circuit

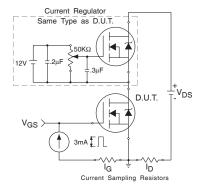


Fig 24a. Gate Charge Test Circuit

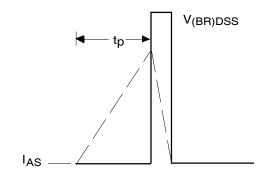


Fig 22b. Unclamped Inductive Waveforms

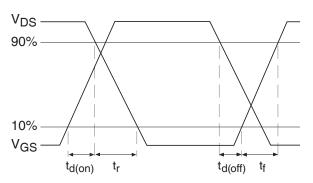


Fig 23b. Switching Time Waveforms

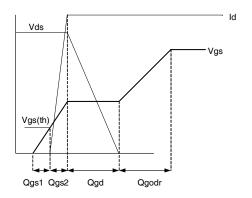
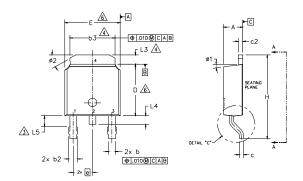
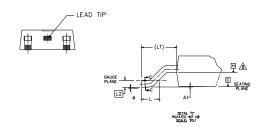


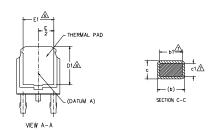
Fig 24b. Gate Charge Waveform

D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)







NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- ⚠— DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION 61 & c1 APPLIED TO BASE METAL ONLY.
- &- DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S Y M		DIMENSIONS				
B O	MILLIM	ETERS	INC	HES	O T E	
L	MIN.	MAX.	MIN.	MAX.	S	
Α	2.18	2.39	.086	.094		
A1	-	0.13	-	.005		
b	0.64	0.89	.025	.035		
b1	0.65	0.79	.025	.031	7	
b2	0,76	1,14	.030	.045		
b3	4.95	5.46	.195	.215	4	
С	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	7	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	6	
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	6	
E1	4.32	-	.170	-	4	
e	2.29	BSC	.090	BSC		
н	9.40	10.41	.370	.410		
L	1.40	1.78	.055	.070		
L1	2.74	BSC	.108	REF.		
L2	0.51	BSC	.020	BSC		
L3	0.89	1,27	.035	.050	4	
L4	-	1.02	-	.040		
L5	1,14	1,52	.045	.060	3	
ø	0,	10*	0,	10*		
ø1	0,	15*	0,	15*		
ø2	25*	35*	25*	35*		

LEAD ASSIGNMENTS

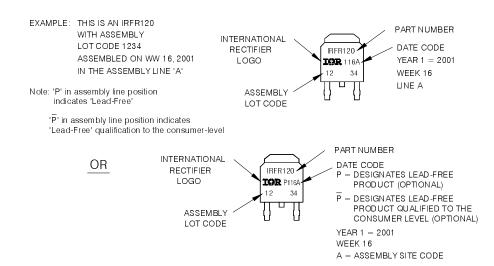
HEXFET

- 1.- GATE
- 2.- DRAIN 3.- SOURCE
- 4.- DRAIN

IGBT & CoPAK

- I.- GATE
- 2.- COLLECTOR
- 3.- EMITTER 4.- COLLECTOR

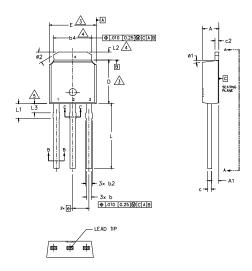
D-Pak (TO-252AA) Part Marking Information

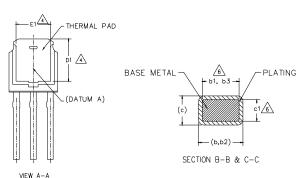


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)





NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- ⚠ DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
- \$- LEAD DIMENSION UNCONTROLLED IN L3.
- ⚠- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.
- 7.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA (Date 06/02).
- 8.- CONTROLLING DIMENSION; INCHES.

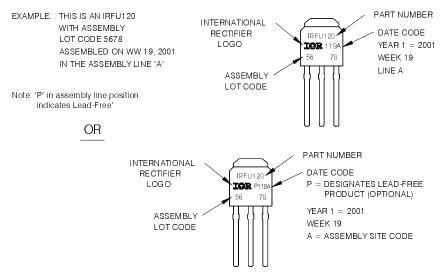
S			N		
M B O	MILLIM	ETERS	INC	HES	0 T E S
L	MIN.	MAX.	MIN.	MAX.	S
Α	2.18	2.39	.086	.094	
A1	0,89	1,14	.035	,045	
ь	0.64	0.89	.025	.035	
b1	0.65	0.79	.025	.031	6
ь2	0.76	1.14	.030	.045	
b3	0.76	1.04	.030	.041	6
b4	4.95	5.46	.195	.215	4
С	0.46	0.61	.018	.024	
c1	0.41	0.56	.016	.022	6
c2	0.46	0.89	.018	.035	
D	5.97	6.22	.235	.245	3
D1	5,21	-	.205	-	4
E	6.35	6.73	.250	.265	3
E1	4.32	-	.170	-	4
е	2.29	BSC	.090	BSC	
L	8,89	9.65	.350	.380	
L1	1.91	2.29	.045	.090	
L2	0.89	1.27	.035	.050	4
L3	1.14	1.52	.045	.060	5
Ø1	0.	15*	0.	15°	
ø2	25 °	35°	25°	35 °	

LEAD ASSIGNMENTS

HEXFET

- 1.- GATE
- 2.- DRAIN 3.- SOURCE
- 4.- DRAIN

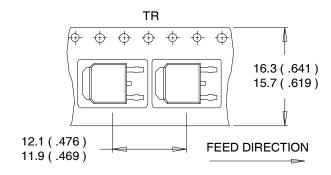
I-Pak (TO-251AA) Part Marking Information

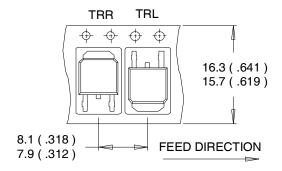


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/www.irf.com

D-Pak (TO-252AA) Tape & Reel Information

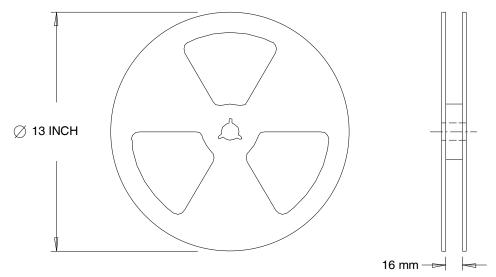
Dimensions are shown in millimeters (inches)





NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Orderable part number	Package Type	Standard Pack		Note
-		Form	Quantity	
IRFR4510PbF	D-PAK	Tube/Bulk	75	
IRFR4510TRPbF	D-PAK	Tape and Reel	2000	
IRFU4510PbF	I-PAK	Tube/Bulk	75	

Qualification Information[†]

Qualification level	Industrial ^{††}		
Qualification level	(per JEDEC JESD47F ^{†††} guidelines)		
	Comments: This family of products has passed JEDEC's Industrial qualification. IR's Consumer qualification level is granted by extension of the higher Industrial level.		
	D-PAK	MSL1	
Moisture Sensitivity Level	D-FAR	(per JEDEC J-STD-020D ^{†††})	
	Not applicable		
RoHS Compliant	Yes		

- † Qualification standards can be found at International Rectifier's web site http://www.irf.com/product-info/reliability
- †† Higher qualification ratings may be available should the user have such requirements. Please contact your International Rectifier sales representative for further information: http://www.irf.com/whoto-call/salesrep/ ††† Applicable version of JEDEC standard at the time of product release.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by T_{Jmax} , starting T_J = 25°C, L = 0.18mH R_G = 50 Ω , I_{AS} = 38A, V_{GS} =10V. Part not recommended for use above this value.
- $\label{eq:loss_def} \mbox{\Large \Im} \ \ I_{SD} \leq 38A, \ di/dt \leq 2031A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- 4 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.

- $^{\circ}$ C_{oss} eff. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

Data and specifications subject to change without notice



IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA Tel: (310) 252-7105

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